Search Notes

Applic	cation/C	ontrol	No.
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10/530,271

Examiner

Matthew C. Landau

Applicant(s)/Patent under Reexamination

YOSHIHARA ET AL.

Art Unit

2815

	SEAR	CHED	
Class	Subclass	Date	Examiner
2577	30, 295, E43.004, E37.608, E34.123, E21.665	6/19/01	\
365	158, [7], 173,269 124.2; 324.1, 324.11, 324.12		
365 ³	724.2', 324.1.		
	324.11, 324.12	7	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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